Supplementary Information (SI) for Journal of Materials Chemistry A. This journal is © The Royal Society of Chemistry 2024

The fabrication of Ti<sub>3</sub>C<sub>2</sub> and Ti<sub>3</sub>CN MXenes by electrochemical etching

## **Supporting information**

Bragg's law and the reciprocal-space metric tensor equation of hexagonal crystal lattices:

$$\frac{1}{n\lambda = 2d\sin(\theta)}, \quad \frac{1}{d^2} = \frac{4}{3} \left( \frac{h^2 + hk + k^2}{a^2} \right) + \frac{l^2}{c^2}$$

## Calculation of charge conducted during the electrochemical etching

Number of electron conducted during etching =  $\sum_{t=24}^{e^{-}} It. \ 6.24 \times 10^{18} C^{-1}$ 

Number of MAX phases unit cell =  $\frac{m_{MAX}}{M_w(MAX)}N_A$ 

*I*= current; *t*= etching time;  $m_{MAX}$ = mass of MAX phases;  $M_w$ (MAX)= molecular weight of MAX phases;

 $N_{\rm A}$  =Avogadro constant



Figure S1. XRD spectrum of Ti<sub>3</sub>AlCN precursor and electrochemically etched Ti<sub>3</sub>CN. (Etching condition:



Figure S2. Infrared spectrum of the aluminium oxide precipitate after all  $HBF_4$  electrolyte residue was evaporated.



Figure S3. XPS N 1s spectrum of EE-Ti<sub>3</sub>CN. Peaks located at 396.4, 397.1, 399.5, and 402.4 eV



Figure S4. XPS C 1s spectrum of EE-Ti<sub>3</sub>CN. peak located at 281.5, 284.7, 286.4, and 288.6 eV are assigned for X-Ti, C-C, C-O, and C=O, respectively.



*Figure S5. XPS Ti 2p spectrum of EE-Ti<sub>3</sub>CN. Peaks located at 455.0(461.2), 455.9* (461.4), 457(462.7), 458.6(464.2), 460.2(466.2) eV are assigned for titanium metal in



Figure S6. Photographs of  $Ti_3AlC_2$  precursor, EE- $Ti_3C_2$  multilayer powder, dispersion of TMAOH

treated EE- $Ti_3C_2$  in water.



Figure S7. SEM images for Ti<sub>3</sub>AlC<sub>2</sub> MAX phase.



*Figure S8. SEM image for EE-Ti<sub>3</sub>CN.* 



Figure S9. TEM image for EE-Ti<sub>3</sub>CN delaminated flakes. (110) diffraction= 1.51 Å. (100) diffraction= 2.58 Å.